

<b>Notice of References Cited</b>	Application/Control No. 10/604,119	Applicant(s)/Patent Under Reexamination ARMAGOST ET AL.	
	Examiner Tianjie Chen	Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,940,355	08-1999	Buckland et al.	369/30.55
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP 08255415 A	10-1996	Japan	DANG et al.	
	O	With Translation				
	P					
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	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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